

ABSTRACT

The apparatus 10 includes a tray 22 for holding a semiconductor device 18, an inspection connector 30 for automatically coupling to a connector 16 of the device 18, a probe 32 for supplying or receiving signals to or from terminals 14A of a device body 14 being in contact with each other, an inspection robot 36 for picking up the body 14 held in the tray and transporting it to the probe to get contact with or close to; a controller 66 to control the robot 36, and a tester 34 to test the device 18 by supplying input signals to one of the connector 30 or the probe 32 and receiving output signals from the other.

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